

UV-EYE®



UV-EYE is a multifunctional tool ideal for surface defect sizing and TAM Panel inspection for fluorescent penetrant and magnetic particle Non-Destructive Testing (NDT).



- Auto focus camera
- UV & white light LEDs
- Adjustable UV and white light intensity
- Provided with Tablet or Notebook PC
- Defect sizing and image capture
- PDF report generation

Technical data

UVA:	365 nm > 1200 $\mu\text{W}/\text{cm}^2$
White light:	> 1000 lux
Measurement Accuracy:	Up to 0.01 mm
Probe Dimensions:	215 mm x 33 mm x 31 mm
USB:	2.0
USB Cable Length:	2.5 m

UV-EYE software enables:

1. PDF report generation
2. Preloaded report formats: Tam Panel Report, Surface defect report.
3. Measurement of indication with easy line, circle or rectangle measurement features.
4. Image zoom feature.
5. Custom calibration feature.
6. Multilingual user interface: English, French, German, Italian.

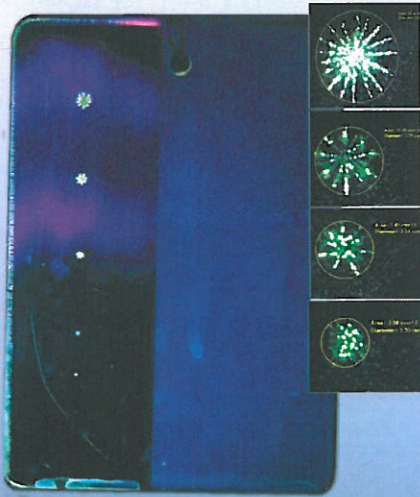







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PSM5 /TAM PANEL DEGRADATION CHECK:

This has become a mandatory test for ensuring consistency of Penetrant System Performance. Difficulty of measuring the star cracks particularly the small stars is now easily done using UV-Eye.

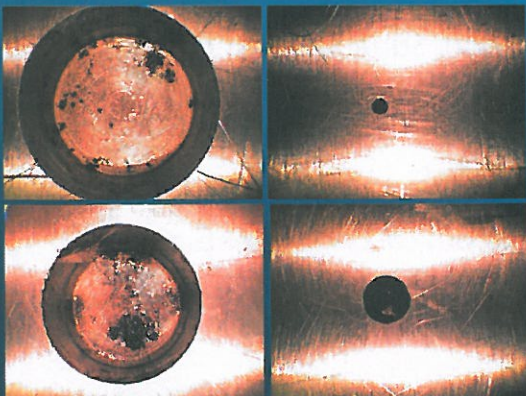


TAM PANEL /PSM5 Report					
Container	R51	Serial No	P-20072		
Comments					
Calibration Details					
Calibration	HDT MASTER FCN	Dev	DS9101112	Operator	DevD
Certificate	R255103	Device	Transparent Comparator		
Diagram	Crack	Value	0.01021		
Remarks					
Diometer	4.802 mm				
Area	18.000 mm				
	0.009 mm				
Diometer	2.937 mm				
Area	4.710 mm				
	0.010 mm				
Diometer	1.870 mm				
Area	2.100 mm				
	0.008 mm				
Diometer	1.900 mm				
Area	0.880 mm				
	0.009 mm				
Diometer	0.400 mm				
Area	0.130 mm				
	0.005 mm				

Tam panel report

DEFECT INDICATION RECORDING AND MEASUREMENT

UV-EYE enables the user to measure and capture surface defect images for report generation. The instrument can be calibrated easily using either UVA or white light with known traceable standards such as transparent comparators or graticules. Accurate measurements can now be made under UVA or white light.



Visual whitelight inspection capability

